Issue Classification | 10826090



I	Application/Con	trol No.
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Samuel G Neway

Examiner

Applicant(s)/Patent Under Reexamination

CHEN, SHI-SHIEN

Art Unit 2626

ORIGINAL						INTERNATIONAL CLASSIFICATION									
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/D	David R. Hudspeth/	5/16/08	O.G. Print Claim(s)	O.G. Print Figure					
(Primary Examiner)	(Date)	11	Fig. 2B					
11.6	U.C. Detect and Testerand Office								

(Assistant Examiner)

(Date)

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